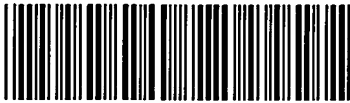


Search Notes

Application/Control No.

10/067,310

Examiner

Ba Huynh

Applicant(s)/Patent under
Reexamination

FUJII ET AL.

Art Unit

2179

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East: USpat, USpgpub, Epo, Jpo, Derwent, IBM-tdb files search updated	1/1/2006	HB